In this talk, we will discuss new advances and innovations from ZEISS in the areas of Scanning Electron Microscopy, specifically with regards to Correlative Light and Electron Microscopy (CLEM), and Array Tomography of large sample areas. Our discussion will focus on new advances in these areas, specifically in Cryo-CLEM utilizing a high resolution confocal detector known as Airyscan in tandem with present cryo-SEM techniques, and in Array Tomography of large sample areas, employing simultaneous scanning of 61 or 91 electron beams in a new kind of multi-beam SEM known as “MultiSEM.” We will be available after the presentation to answer questions for further discussion.